PCN Number:			20140605000					PCN Date: 06/13/20		06/13/2014		
Title:	Title: Qualification of TI Clark and NSE as Additional Assembly and Test Site for Select Devices											
Customer	r Contact:	PC	PCN Manager		Phone		+1(214)480-6037		Dept:	Quality Services		
Proposed	1 st Ship Dat	e:	09/13/2014		4		•		ate Provided at Sample quest			
Change T	ype:											
Asse	mbly Site					Design			Wafer Bump Site			
	mbly Process				D	ata Sh	eet		Wafer Bump Material			
	mbly Materials						nber change				p Process	
	anical Specific				_	est Sit			Wafer			
Packi	ing/Shipping/l	abe	eling		Test Process			Wafer Fab Materials				
									Wafer	Fab I	Process	
						PCN I	Details					
Description	on of Change	:										
Texas Instruments Incorporated is announcing the qualification of TI Clark and NSE as additional assembly/test site for select devices listed in the "Product Affected" Section. Current assembly sites are as follows and no material differences between assembly sites. • Group 1 Device: TI Malaysia to TI Clark • Group 2 Device: TI Clark to NSE Test coverage, insertions, conditions will remain consistent with current testing and verified with												
test MQ.												
Reason for Change:												
Continuity of supply.												
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):												
None	None											

Changes to product identification resulting from this PCN:

Group 1 Device: TI Malaysia to TI Clark

Assembly Site		
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA
TI Clark	Assembly Site Origin (22L)	ASO: QAB

ASSEMBLY SITE CODES: TI Malaysia = K , TI-Clark = I

Group 2 Device: TI Clark to NSE

Assembly Site		
TI Clark - Philippines	Assembly Site Origin (22L)	ASO: QAB
NSE Thailand	Assembly Site Origin (22L)	ASO: NSE

ASSEMBLY SITE CODES: TI CLARK = I, NSE = J

Sample product shipping label (not actual product label)



(L)T0:1750 5A



(1P) SN74LS07NSR (a) 2000 (P) 0336 31T)LOT: 3959047MLA 4W) TKY(1T) 7523483\$12 (2P) REV: (V) 0033317 (21L) CCO:USA 0033317

(20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected: Group 1 Device (TI Malaysia to TI Clark)

TPS51206DSQR-P TPS51206DSQT TPS51206DSQR

Product Affected: Group 2 Device (TI Clark to NSE)

PCM3070IRHBR PCM3070IRHBT TLV320AIC3204IRHBR | TLV320AIC3204IRHBT

Qualification Data: Group 1

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

Qual Vehicle: TPS51206DSQ (MSL2-260C) **Package Construction Details** Assembly Site: TI Clark 4208625 Mold Compound: # Pins-Designator, Family: 10-DSQ, WSON Mount Compound: 4207768 Lead frame (Finish, Base): 0.96 Mil Dia., Cu NiPdAu, Cu Bond Wire: **Test Results Qualification:** Plan Reliability Test Conditions Sample Size/Fail **Pass** Manufacturability (per mfg. Site specification)

Reference Qualification Data

Reference Qualification Data							
Qual Vehicle: TPS51518RUKR (MSL2-260C)							
Package Construction Details							
Assembly Site:	TI Clark	Clark Mold Compound:			4208625		
# Pins-Designator, Family:	20-RUK, WQFN	-RUK, WQFN Mount Compound:		4207768			
Lead frame (Finish, Base):	NiPdAu, Cu	PdAu, Cu Bond Wire:			0.96 Mil Dia., Cu		
Qualification: Plan	☐ Test Results						
Doliability Tost	Conditions	Conditions		Sample Size/Fail			
Reliability Test	Conditions		Lot#1	Lot#2	Lot#3		
Electrical Characterization	-	-			-		
**Life Test	170C (420 Hrs)	170C (420 Hrs)		77/0	77/0		
**Biased HAST	130C/85%RH (96	130C/85%RH (96 Hrs)			77/0		
**High-Temp Storage Bake	170C (420 Hrs)	170C (420 Hrs)			77/0		
**Temp Cycle	-65C/+150C (500	-65C/+150C (500 Cyc)			77/0		
Moisture Sensitivity	Level 2-260C	Level 2-260C			12/0		
Manufacturability	(per mfg. Site spe	(per mfg. Site specification)			-		
Notes **- Preconditioning sequence: Level 2-260C.							

Qualification Data: Group 2

Qualification Data : Group 2								
This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.								
Qı	ial Vehicle : SN0509	043RGC (MSL3-260C)					
	Package Constr	ruction Details						
Assembly Site:	NSE	E Mold Compound:			CZ0134			
# Pins-Designator, Family:	64-RGC, VQFN	Mount Compound:	PZ0031					
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	2.0 Mil	1il Dia., Au				
Qualification: Plan	☐ Test Results							
Reliability Test	Conditions	Conditions		Sample Size/Fail				
Reliability Test	Conditions			Lot#2	Lot#3			
Electrical Characterization	-		Pass	Pass	Pass			
**Life Test	140C (480 Hrs)		113/0	116/0	116/0			
**HAST	130C/85%RH (96	5 Hrs)	77/0	77/0	77/0			
**Autoclave	121C, 15 PSIG, 2	121C, 15 PSIG, 29.7 PSIA (96 Hrs)		77/0	77/0			
**Thermal Shock	-65C/+150C (100	-65C/+150C (1000 Cyc)			77/0			
**High-Temp Storage	170C (420 Hrs)	170C (420 Hrs)			77/0			
**Temp Cycle	-65C/+150C (500	-65C/+150C (500 Cyc)			77/0			
Solderability	8 Hrs Steam Age	8 Hrs Steam Age			22/0			
Salt Atmosphere	24 Hrs		22/0	22/0	22/0			
X-ray	(top side only)		5/0	5/0	5/0			
Manufacturability	(per mfg. Site spe	(per mfg. Site specification)			Pass			
Notes **- Preconditioning sequence: Level 3-260C.								

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com